

<b>Notice of References Cited</b>	Application/Control No. 10/724,374	Applicant(s)/Patent Under Reexamination BAE ET AL	
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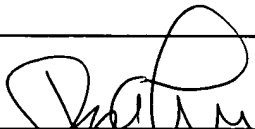
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	A	US-5,190,700 A	03-1993	Watanabe et al.	252/609
	B	US-5,519,077 A	05-1996	Drewes et al.	524/114
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	N	JP 61-9451 A	01-1986	Japan	Akimine et al.	C08L 27/04
	O	JP 4-268355 A	09-1992	Japan	Kano et al.	C08L 27/06
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JP 61-9451 (abstract in English)
	V	JP 4-268355 (abstract in English)
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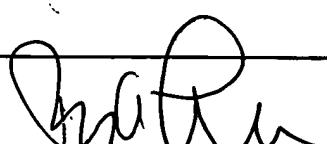
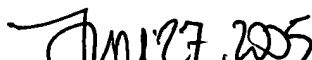
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	A	US-6,245,846 B1	06-2001	Daniels et al.	524/409
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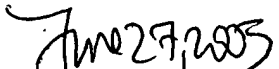
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	M	US-			

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